Se	earch	Notes	

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Application/Control No.	Applicant(s)/Patent under Reexamination
10/690,230	REEDER ET AL
Examiner	Art Unit
William Jung	3768

SEARCHED				
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INTERFERENCE SEARCHED				
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SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
see attached search history	7/23/2006	WCJ